
**Surface chemical analysis — X-ray
photoelectron spectroscopy —
Procedures for assessing the day-
to-day performance of an X-ray
photoelectron spectrometer**

*Analyse chimique des surfaces — Spectroscopie de photoélectrons X
— Modes opératoires d'évaluation de la performance au jour le jour
d'un spectromètre de photoélectrons X*

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Foreword

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